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NICD SPACE BATTERY TEST DATA ANALYSIS PROJECT PHASE 2

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Prepared for
GODDARD SPACE FLIGHT CENTER
Greenbelt, Maryland
CONTRACT NAS 5-10203

MAUCHLY SYSTEMS, INC.
MONTGOMERYVILLE INDUSTRIAL CENTER
Montgomeryville, Pa.



FIRST QUARTERLY REPORT

FOR

NICD SPACE BATTERY TEST DATA ANALYSIS PROJECT

PHASE 2

(JANUARY 1, 1967 - APRIL 30, 1967)

CONTRACT NO.: NAS 5-10203

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Attention: Mr. Eugene Stroup Contract Manager

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ABSTRACT

NiCd cell-failure-characteristic data, for cells made by four batterycell manufacturers, was computer examined by a technique of cryptology or cryptanalysis.

This is a new use of cryptanalytic technique which was previously only used by security agencies to 'break' ciphers and codes. The Crane failure characteristic reports were assumed to contain hidden information or information not readily extractable by manual analysis. This assumption proved correct when the data was treated like a code or cipher. Application of cryptanalytic technique extrapolated information which identified specific cell failure mechanisms accountable to individual battery-cell manufacturers. This procedure, referred to in this report as "TRI-GRAM Failure Characteristic Technique", is applicable to any coded data.

Cell failure characteristic/cycling environmental parameter analysis will be performed to correlate failure mechanisms with single and combined environmental effects.

INTRODUCTION

This is the first quarterly report, covering the period from January 1, 1967 to April 30, 1967, for contract number NAS 5-10203, Phase 2, in accordance with Proposal No. 17-1216 BATT entitled "Techniques in Space Battery Test Data Analysis, Reduction and Correlation".

The following objectives are set forth as goals to be attained by this study:

- 1. Develop and demonstrate methods for prediction of cell failure as a function of failure characteristics and operating constraints.
- 2. Develop and demonstrate new techniques for extraction and presentation of information from a large volume of space battery test data.
- Develop improved methods for the collection and handling of the Crane data.
- 4. Develop mathematical models related to battery tests as practicable and useful to the battery user.
- 5. Instruct Crane in the functioning and use of computer programs and techniques developed under this contract.

Since about January, 1963, the Secondary Battery Section of the Quality Evaluation Department at NAD Crane, Indiana has been cycling, monitoring, and collecting data on sealed nickel-cadmium space battery cells. Part of these data consists of failed-cell post-mortem autopsy reports, in detailed English, performed on every cell after failure.

INTRODUCTION (Cont'd)

After close examination of these autopsy reports, covering several hundred cells, it was considered that valuable information, particularly information on failure-mechanisms, was hidden or occulted in the mass of data. Manual analysis of the cell-autopsy data was impossible because of the large mass of varied failure characteristics contained therein.

A technique used in cryptology, for the purpose of 'breaking' or 'cracking' secret ciphers and codes, was applied to the mass of failure characteristic data; treating the data itself as a secret code containing a message of sorts. The use of cryptology and cryptanalytic technique as applied to industrial or failure data is believed to be new and novel. This technique has heretofore been in the domain of secret intelligence agencies and secret agents. Modern cryptography makes full use of mathematics and electronics to gather information from seemingly meaningless signals or data.

The failure characteristic data, reported by Crane, were converted into a coded structure of twenty-one different failure characteristics represented by the letters A through U. Table A shows the code legend. These coded failure characteristics were entered onto punch cards; each card, representing one battery pack, with both pack and manufacturer identification. A maximum card field of up to seven characters was allowed to represent the coded failure characteristic information for each identified cell. This convention permitted coded information for a pack of up to ten cells to be contained in one punch card.

A computer was programmed, the program being an application of cryptology or cryptanalysis, to examine the coded data and to construct tables showing the frequency of failure by one characteristic jointly with each of of the other failure characteristics. The resultant tables were called

INTRODUCTION (Cont'd)

"BIGRAM" tables because they indicate the combinatorial frequency of any two coded failure characteristics. Information regarding cell failure by specific "BIGRAMS" was found to apply to individual cell manufacturers. More information concerning "BIGRAM" tables can be found in the Appendix of this report, page 38.

Certain success was achieved by the use of "BIGRAM" tables but it was considered that much more specific failure mechanism information could be gained by measuring the joint frequency of any three coded failure characteristics. A "TRI-GRAM" frequency program was then the logical evolution of the "BIGRAM" technique.

The "TRI-GRAM" technique is so called because it indicates the combinatorial frequency for any three coded failure characteristics with each other. It is also a cryptanalytic process.

The "TRI-GRAM" technique has enabled us to pinpoint specific failure mechanisms assignable to individual battery cell manufacturers who can then evaluate possible design/material imperfections in their product. This manufacturer/failure mechanism relationship is dealt with at length in the discussion section and appendix of this report.

The major purpose in the use of this cryptanalytic technique is that it enables the correlation of observed 'N'-gram frequencies with probabilistic frequencies based on mono-gram occurrences. 'N'-gram probability distribution tables are constructed from ('N'-1) gram distribution tables. When the observed 'N'-gram occurrence differs from the probabilistic 'N'-gram table, the observed 'N'-gram of coded failure characteristics is highly suspect of being a failure mechanism.

INTRODUCTION (Cont'd)

Observed mono-gram frequency distributions are the basis for "BIGRAM" probability tables; observed "BIGRAM" distributions are the basis for "Tri-Gram" probability tables, etc. 'N'-gram distributions are constructed until 'N' is too high to permit sufficient frequency for observation. For additional 'Bigram' information see page 38.

Analogous to this procedure is the relative frequency of usage for letters in the English language. In a typical sample of English, for example, about 13 percent of the letters will be E's, 9 percent T's, 8 percent O's, and 2 percent P's. Although these frequencies will vary from sample to sample, for large bodies of text they are reliable enough to constitute one of the main tools of cryptanalysis. From such monogram frequencies one can calculate the frequencies which letter-pairs (Bi-grams) would have if the letters were in random sequence. The frequency of Bi-grams obtained from English usage are, of course, much different because the sequence of letters is not a random one. Cryptanalysis uses such frequency information to detect message structure.

DISCUSSION

Battery and cell failure data was extracted from the "Monthly Progress Report on National Aeronautics and Space Administration Space Cell Test Program" published by the Secondary Battery Section of the Quality Evaluation Department at NAD, Crane, Indiana, who is conducting the test program. The cut-off date for data used in this report was December 31, 1966.

As cells fail during cycling they are removed from the pack, opened, and a post-mortem examination is performed. The examination results are reported in descriptive English, such as the following report for Pack 5, Cell 3: "Low Voltage Discharge, Normal Voltage Charge, Still Under Pressure When Opened, Weak Tab to Plate Welds, Short Caused by Excess Scoring, Migration of Negative Plate Material, Separator Completely Deteriorated".

A simple code structure of failure characteristics, as defined by Crane, was devised. Table A shows the code legend. A maximum of seven coded failure characteristics per identified cell is entered into a punch card that also has pack and manufacturer identification. The maximum of seven coded failure characteristics is a convention to permit the failure characteristic history for all failed cells in one identified battery pack of up to ten cells to be represented by one punch card.

As example, Table B is a tabular representation of coded failure characteristic information provided in the Crane post-mortem reports. Examination of Table B will show that the reported failure characteristics for the previously mentioned Pack 5, Cell 3, are encoded BLQTKFC. In Table B, columns are cell numbers while row headings contain pack and manufacturer identification.

DISCUSSION (Cont'd)

It was assumed that much valuable information was contained in the mass of failure characteristic data. It was also noted that manual analysis of this conglomerate mass of data was difficult if not impossible. A technique, new and novel in industrial application, was applied to the data to extrapolate meaningful information. This technique is used in cryptology or cryptanalysis by intelligence organizations to extract a "message" from an apparently meaningless signal or body of data. A computer program was written to examine the data and to apply the cryptanalytic technique of measuring the combinatorial frequency of any three coded failure characteristics jointly with each other. The program output consisted of 1330 tally counters each of which indicated the occurrence frequency of a specific three-letter combination from all of the twenty-one letters used to code the failure characteristic data. (See Table A) The resultant tally tables are called "TRI-GRAM" frequency tables because each counter refers to joint frequency of three coded failure characteristics. There are 1330 three-letter permutations possible from the twenty-one code letters used.

"Tri-Gram" frequency tables were constructed for each of four manufacturers individually and for the same four manufacturers in total. Examples of portions of these "Tri-Gram" frequency tables follow as Table C. Pages C-1 through C-4 are the first sheet of each table constructed for the four individual manufacturers. Pages C-5 through C-18 are the complete "Trigram" frequency table, consisting of 1330 two-digit tally counters, for the total of the four manufacturers. It can be seen that Page C-5 is the total of pages C-1 through C-4.

Table D is a partial listing by manufacturer of total and partial "Tri-Gram" frequencies accountable to that identified manufacturer. The column headed "TRI-GRAM CODE" indicates the specific combination of coded failure characteristics. The column headed "PART" indicates that

DISCUSSION (Cont'd)

manufacturers portion of the total frequency, specified by the column headed "TOTAL", for all four manufacturers. Examination of Table D will show that individual manufacturer's cells were responsible for the total of many individual "Tri-Gram" failure characteristics or failure mechanisms. It may be seen that manufacturer No. 2, for example, is responsible for all occurrences of BCK:

B = Low Voltage Discharge

C = Separator Deteriorated, Dissolved, Etc.

K = Excess Scoring of Case

Manufacturer No. 2 was responsible for all occurrences of failure characteristic K.

Manufacturer No. 3 was responsible for all occurrences of BIO:

B = Low Voltage Discharge

I = Blistering on Positive Plate (s).

O = Ceramic Short

Manufacturer No. 3 was responsible for all occurrences of failure characteristic O.

Table E is included for reference only. Table E is listings, by manufacturer, of specific "Tri-Gram" codes with the frequency of 50% or more assignable to the indicated manufacturer. An asterisk (*) beneath a code indicates that 100% of that code frequency is assignable to the indicated manufacturer.

With this application of the "Tri-Gram Failure Characteristic Technique", it is possible to determine which single and/or triple combination of failure characteristics give insight to the identification of specific failure mechanisms assignable to individual designs or manufacturer.

NEW TECHNOLOGY

A new and novel application of a technique used in cryptology or cryptanalysis is being used to extract information from a mass of industrial data.

This technique has long been employed in the realm of intelligence organizations and secret agents to 'break' or 'crack' ciphers and codes. This is the first industrial application of this cryptanalytic process.

Cell failure characteristic data reported by NAD Crane was examined and assumed to contain much important information. This data covered several hundred battery cells with many types of failure characteristics for each cell. The resultant mass of data was too large, varied, and in unsuitable form for usual means of analysis; also, the data were so structured, unavoidably, to make manual analysis all but impossible.

The many kinds of failure characteristics reported by Crane were structured by Mauchly Systems, Inc., into a code of twenty-one possible types represented by the letters A through U. The cryptanalytic process of measuring the combinatorial frequency of any three code letters was programmed on a computer. The resultant computer output was a table of 1330 tally counters indicating the frequency of occurrence of each identified three-letter combination within the twenty-one letter code structure. Because this program indicated the combinatorial frequency of three letters, it was called the "Tri-Gram Failure Characteristic Technique".

The original assumption, that the cell failure characteristic reports contained much important information proved correct. Information extrapolated from the mass of data indicated that certain failure characteristics and failure mechanisms could be assigned to specific manufacturers and cell designs.

NEW TECHNOLOGY (Cont'd)

Application of the "Tri-Gram Failure Characteristic Technique", to any coded data, enables correlation of failure characteristics and failure mechanisms to manufacture/design defects and to environmental effects.

PROGRAM FOR NEXT REPORTING INTERVAL

1. "Tri-Gram" Tables:

"Tri-Gram" frequency tables will be constructed for several individual and combined cycling environmental parameters. Effort will be made to determine environmental effect (s) on failure characteristics and failure mechanisms.

2. Temperature:

A temperature-failure analysis is in progress. Effort will be made to ascertain if cell-temperature fluctuation-patterns are indicative of impending cell failure.

CONCLUSIONS AND RECOMMENDATIONS

Much valuable information concerning manufacturer/design effect on failure characteristics and failure mechanisms has been gained by application of the technique described earlier in this report. This information can be used by cell manufacturers to assay the extent of possible defects in their product within all operating conditions and to evaluate the interrelating effects of new components with each other and with standard parts. Specific areas of concern are pinpointed for attention by the cell-design and quality control engineer. As example, manufacturer No. 2 was responsible for all cell failures involving "Excess Scoring of Case", manufacturer No. 3 was responsible for all cell failures involving "Ceramic Short", and manufacturer No. 4 was responsible for all cell failures involving "Extraneous Material Between Plates".

The ultimate purpose of this work is to provide the engineer with a method to assess the potentialities of space-battery-cells relative to various environmental and functional parameters, permiting correlation and selection within space mission operational requirements and constraints.

CONCLUSIONS AND RECOMMENDATIONS (Cont'd)

The "Tri-Gram" frequency technique is limited only by the necessity for coded input. The major advantage of this technique is the capability gained to extract information "hidden" within a large mass of varied data.

It is recommended that cell post-mortem reports be expanded to include more physical and chemical data such as plate weight-loss and electrolyte PH, etc. Such additional information should further pinpoint specific failure mechanisms and permit earlier and more exact prediction capabilities.

TABLES

FAILURE CHARACTERISTICS

- A. Low Voltage Charge.
- B. Low Voltage Discharge.
- C. Separator: Deteriorated, Dissolved, Burned, Pinpoint Penetration, Short.
- D. Plate Material Shorted Through Separator.
- E. Separator Impregnated With Negative Plate Material.
- F. Migration of Positive and/or Negative Plate Material.
- G. Extraneous Material Between Plates.
- H. Deposit on Positive and/or Negative Terminals.
- I. Blistering on Positive Plate(s).
- J. Plate(s) Stuck To Case.
- K. Excess Scoring of Case.
- L. High Pressure, Bulge, Convex Side(s)
- M. Concave Side(s), Short(s) Due To Internal Shift.
- N. Broken Seal(s): Ceramic, Glass
- O. Ceramic Short
- P. Electrolyte Leak, Weight Loss, Separator Dry, Electrolyte Shorted Out Cell.
- Q. Tab(s): Burned, Broken, Welds Weak.
- R. Third Electrode Shorted to Plate.
- S. Cell Blew Up.
- T. Circuit: Short, Open.
- U. High Voltage Charge.

EXAMPLE OF FAILURE CHARACTERISTIC INFORMATION PROVIDED BY CRANE AND CODED BY MAUCHLY SYSTEMS, INC.

	01	BHQTKFC TPLDCQ	8PE	ABPCF		ABCD		APGC		BUPL		BFC1	ABEC	ABO				APDCG	AUG			ABPDCG		a .	109			BUFT			QCFE	ABFCI		BLCF	o.	
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	co	11	ĺ	ABPL		BE	!	APO				ABIFC						APDCF	APL.	BCK	ABPTKFC	BUPCEG		۵	ABPO	ABO	ВС	ВРF	ВО	ВО		BUC1		ABLEFC	α	MABMO
	7	ABDQKCE	ВРСБ	BPL		BKTOC	APFC	ABPOCE		ABOI	BO	ABIFC	80		BULO		BLOKC	ALDF	APL	CABCO	CT	Œ	PTL		BOPIC		BOU	BUTCG	B0 I	ABO	QTC			BUFCE		ABPE I LMABMO
α	9	BTKFC BEFCQL	BPCD	ABPE		BOKFC	ABPCEO	ABPE					BCDT		BPMO	втсе	BLQD		ABDO	BHPGKDCABCG		ABDGECG	ВОН		BUCE 10	ABPO	BTPQUC	BUPTCQ	ВО	ВРС	ď	G			۵	BHLMTOFBULHNICBULMNP
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CEI	4	BUCP	BCE 1		O	DTQ				ABO1C	BUPL	BFC1	ABEC			BLTKFC	ABCD		ABTIE		ABCOK	a	ABPT	σ.	ABOI					ABPIFCO	BTCGA					
	ო	BOKFC	,	AC	BLOTKFC		APOC		ROICP		ABO			BULO	BPL	BCD	¥	ABPCF	BUG			ABPDCEQ	8P	σ.	ABPO	BUP		BUTGC	BO 1		BUTCO	BFC	ABHKFT	TGDFC	<u>α</u>	BOLMIP
	8	ABKDGC	ABPQ		BUKFTC		APEFCO	ABPCEG	BUHF I CPRO I CP	ABOCE 1L	BUO			ABCIL		ABFCQ		ACE	APO			BUDC		۵		ABLO	BPTQUC	BUPGT	ВО			BUHFCI			۵	
	-	BUQKT BLKFC		ABCL			APNCFO	ACE	THFIC		BUPL		BDCET	ABOL	ABOIE	ABKFC	۵		ABTD	TODK	T C	ABPGCQ	BPT	a .			BHOFC			ABLOP		THC			Q .	
		PACK 1 2 2 2			53 53		7 4	4	ო					n	n	Ŋ	N		4	N	Ŋ					38 3			41 3			44	50 2	52 4	57 5	

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This page features every three letter
             combination that contains the letter
            First page of a "Tri-Gram" table.
              for the indicated manufacturer
 D 8
 F 50 08
 CELLS
 2000 F 00 D 00
 989999999
 PACKS
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 MANUFACTURER
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    Ä
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 MANUFACTURER
 1 - - 0 J 0 X - J 0 Z 0 Z 0 0 0 Q 0 Q 4 X 0 N 0 + 0 J 0
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 A
C
   A
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 0 4 T 0 0 0 R 0 0 0 F 0 D 0
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 7 4 E W Z O O 4 G W Q O C O O O O O O
3
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ON
 MANUFACTURER
 0 % D 4 M 0 M 0 0 0 E 0 H 5 J 0 X 0 J 0 E 0 X 0 0 0 0 F 0 H 0 0 0 0 F 0 J 0
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28
F 8 ⊃ 8
20 L 80 D 00
α 0 α 0 ⊢ 6 ⊃ 0
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occurrences for all four manufacturers
               pages
                  Pages C-5 through C-18 are a listing
                  of a complete "Tri-Gram" frequency
              Every entry on this page is the sum
               of the corresponding entries on
                   This table specifies the
> 8
F $3 ⊃ 8
00 + 41 ∪ 00
                C-1 through C-4.
8 2 8
 AC
  P
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       AG
        Ā
         A A A
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31 U O S J O Z 4 J O E 4 Z O O N T 5 Q O N O H N D N

03 F 1 0 40 Q Q R O N O F O D E 010010000 H 4100 0 0 0 1 1 4 E 0 S E 0 M T 0 0 M T 0 0 0 H M D 10

20 01 0 C 02 0 m a 0 a 0 + 0 D 0

20

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KM N O P G R S T U

KM N O P G R S T U

KN O P G R S T U

KO OO OO OO OO OO OO OO

KO P G R S T U

KO P G R S T U

KO OO OO OO OO OO OO

KO OO OO OO OO OO

KR S T U

KR S T U

KS T U

KS T U

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KS T U

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155
155
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161
161
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LN N O P Q R S T U
02 02 05 01 00 00 04 02
LN O P Q R S T U
00 05 00 00 00 05 05
LD Q R S T U
01 01 00 03 14
LQ R S T U
00 00 00 00 02
LR S T U
LR S T U
LR S T U
LS T U
LS T U
LT U
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MN O P Q R S T U
OO 04 00 00 00 01 00
MP Q R S T U
O1 00 00 02 03
MQ R S T U
O0 00 02 03
MQ R S T U
MR S T U
MS T U
MS T U
MT U

NO P Q R S T U
01 00 00 00 01 00
NQ R S T U
00 00 00 02 04
NQ R S T U
00 00 00 00 00
NS T U
NS T U
NS T U
00 00 00 00
NS T U
00 00 00
NS T U
00 00 00

 RS T C 00 00

ST U

15 PACKS

TRI-GRAM CODE	PART	TOTAL
BQT	8	13
BTU	8	12
CQU	6	11
CTU	6	8
PQT	4	7
PQU	4	8
PTU	4	4
QTU	7	8

11 PACKS

TRI-GRAM CODE	PART	TOTAL
ABK	8	8
AKQ	4	. 4
BCK	22	22
BDK	4	4
BFK	15	15
BFT	7	13
$\mathbf{B}\mathbf{K}\mathbf{L}$	5	5
BKQ	13	13
CKQ	12	12
DFK	2	2
DQT	4	4
KQT	5	5
KTU	3	3
LQT	2	4

49 PACKS

TRI-GRAM CODE	PART	TOTAL
АВН	6	10
ABI	29	42
ABO	34	34
ACI	15	26
\mathbf{AIL}	15	20
AIO	18	18
BCI	28	47
BFH	11	22
${f BIL}$	23	31
BIO	26	26
BIP	16	16
$_{ m BLP}$	21	24
CHT	10	14
EIO	5	5
\mathtt{FIL}	7	10
ILO	11	11
\mathbf{LPU}	14	14
$_{ m LQT}$	2	4
MPU	3	3
NPU	4	4

17 PACKS

TRI-GRAM CODE	PART	TOTAL
ABD	16	29
ABP	15	30
ABQ	12	24
ACP	17	24
BDL	11	16
BEP	10	11
BLT	13	18
CEP	9	9
CPQ	14	24
DLT	8	11
EPQ	7	7
GIL	2	2
GLT	3	3

TRI-GRAM FAILURE CHARACTERISTIC CODES THAT ASSIGN 50% OR MORE OF THEIR TOTAL FREQUENCY COUNT TO THE IDENTIFIED MANUFACTURER.

AN * BELOW TRI-GRAM CODE DENOTES THAT THE INDICATED MANUFACTURER IS ACCOUNTABLE FOR THE TOTAL FREQUENCY OF THAT SPECIFIC CODE.

MANUFACTURER NO. 1 15 PACKS 66 CELLS AHI AGT BGT BTU CET CQU CTU DET FTU PGT PQU PTU GTU * * *

MANUFACTURER NO. 2 11 PACKS 47 CELLS BKQ BKT BKU CDH BKP BFK BFT BHK BKL AKG AKT APT BCK BDK BEK

* * * * AHK AKP AEK * ABK a

DKG DKT DHQ DKP OHD O. F CKU DEK DFK CKT O S S C P CHO CKL CEK CFK CHK CDK CDQ Ŋ

FIU HKP HKG HKT HGT # KP FKO FKT FKU FPT * * * * FT FKL # ELQ Щ ***** О DOT EFL 20,00 9 N

2 KLT KPQ KPT KQT KQU KTU LPQ LQT * * * * *

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* AE	AMP TW	BFH	0 *	B *	OFO U	* CI &	* CO *	# POD *	O # *	T *	G01 *
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ACI	A10	* BDM	Z 1 0 *	₩ ₩ ₩	CFG	유	Ø ₩ ₩	0 *	₩ FOU	F *	π * σ α
ACH	Ψ I ¥	B01	¥ B	OW #	CE 0 ★	OH D	Ο Σ V	010	Ω Σ ₩	F F10	<u>г</u> О
A B0 ★	AIL A	вон	BH	Z W W *	CEI	0 1 8 8	در *	W 1 Q *	я 4 Р	FIT	F07 *
* ABM	A *	BOF	i B	BL∪ *	₩ CD *	Z I V	CLa	DF∪ *	# *	FIG	₩ •
ABI	AHO *	# BCO	BG1 *	BLP	CDL	× C	C P	DFT	# FL	<u>r</u> ∗	i. ∗ G
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m	ო	m	m	n	rs.	m	m	m	ო	ო	ო

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HLM HLN HLO
                         HOU HPG HPT
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MANUFACTURER NO. 4
17 PACKS 76 CELLS

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DGG DGT * CEG BEF T N T ABG ABT ACE ACP ACG ACT ADL ADG ADT AEF AEP AEG AET AFP AFT AGL 900 EQU FGT CEG CEP ₽GL * BDT BDO CGG CGT CNP CNQ CPQ DEG DEG DFG DFP * * * * * * EIT EPO EPT EPU EGT BIT BLT BOP CDG CDQ CDP CEF вор BDL 806 801 * EFP EFU EGO BCG BDE D * ANG APG APT BGP BGQ BGT * DLT DPQ DPU DQU DTU EFL 6TU NPQ * CG₽ * Д О. « BEU BGL * AGT AIT ALT CGL * ე ე ***** GLT * CEU CFG CG1 BET GIT DGU DIL* **A**G0 BEG ₽ **!** | **A**GP BEP CET 0 2 1L *

APPENDIX A

"BIGRAM" TABLES

"BIGRAM" TABLES

This section is presented for background and reference value only.

The Crane Test Program goes beyond simple life testing where only cycle of failure is recorded. As cells fail during cycling they are removed from the pack which is continued on cycling if three cells in a five pack or five cells in a ten pack remain. All removed, failed cells are opened and a post-mortem examination is performed. Results of such examination are included in the "Monthly Progress Report on National Aeronautics and Space Administration Space Cell Test Program" with complete cell and pack identification. The examination results are reported in descriptive English, such as the following report for pack 15, Cell 4: "Low Voltage Discharge, Low Voltage Charge, Migration of Negative Plate Material through Separator, Hot Spots Around Pinpoint Penetration, Blistering on Positive Plate, Separator Deteriorated".

A simple, experimental code structure of failure characteristics, as defined by Crane, was devised. Table A, page 11 shows the code legend. Table B, page 12 is a tabular presentation of the failure characteristic information provided in the Crane post-mortem reports. Columns are cell numbers, while row headings contain pack numbers and the manufacturer's code number. Table B is included for reference value only.

A computer was programmed to examine the coded failure characteristic data and to produce as output "BIGRAM" tables showing frequency of failure by one characteristic jointly with each of the other failure characteristics. Table V, page 40 shows joint frequencies for Manufacturers 1, 2, 3, and 4. Tables W, X, Y, and Z show the joint frequencies by individual manufacturers. The tables may best be read by

"BIGRAM" TABLES (Cont'd)

arranging the code letters of the desired couplet of failure characteristics in alphabetical order and then finding the intersection of the column headed by the first letter with the row headed by the second letter. Thus, in Table V, the total frequency of the joint failure characteristics of "B" and "N" for the four manufacturers is 7. The use of the computer in constructing these "BIGRAM" tables was invaluable. The computer accomplished in minutes correct tables that would have consumed many hours of error producing hand work.

The circled numbers in Tables X, Y, and Z indicate that cells made by the subject manufacturer accounted for all the indicated joint characteristics of failure. It can be observed that certain failure characteristics are totally accounted for by cells made by a given manufacturer. A more complete analysis would indicate those occasions where a majority of joint failure characteristics were accounted for by a given manufacturer's cells. This is illustrated by the numbers with dotted circles in Table Z.

With this technique, valuable information not available with other means can be gained. A computer program, now in the writing, will construct "TRIGRAM" tables. The "TRIGRAM" tables will show the frequency of any three failure characteristics jointly with each other.

Effort will be made to determine correlations, if any, between cycling parameters and failure characteristics.

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